

## Room 4

### Keynote session 4 (Measurement technologies)

KS4-1 Keynote Speaker: Prof. José A. Yagüe-Fabra

Influence of relative intensity in metal-polymer assembly evaluation by X-ray computed tomography (GS12-06)

Daniel Gallardo, Lucía Díaz, José A. Albajez and José A. Yagüe-Fabra

KS4-2 Keynote Speaker: Prof. Giovanni Moroni

Comparative analysis of surface determination techniques in coordinate metrology with X-ray computed tomography (OS19-07)

Huan Shao, Federico Pirillo, Stefano Petrò and Giovanni Moroni

KS4-3 Keynote Speaker: Dr. Gaoliang Dai

Top-down and bottom-up traceability approaches for applied nanodimensional metrology (OS15-06)

Gaoliang Dai and Jens Fluegge

### Feature session 4 (Nano-scale measurements and calibrations)

FS4-1 Feature Speaker: Dr. Jonghan Jin

Multi-wavelength interferometer for measuring absolute distances using numerous frequency modes of the electro-optic comb (OS15-01)

Jonghan Jin, Jungjae Park and Yoon-Soo Jang

FS4-2 Feature Speaker: Prof. Xin Xiong

Research on conjugate differential interferometric self-calibration method for large-scale planar variable-line-spacing gratings (OS15-04)

Xin Xiong, Chenguang Yin, Ziran Chen, Xiaokang Liu and Wei Gao

FS4-3 Feature Speaker: Dr. Giacomo Maculotti

Towards Nanoindentation Metrological Digital Twin: traceable automated procedure for out-of-control measurements identification (OS15-05)

Giacomo Maculotti, Rachele Bertolini, Gianfranco Genta, Lorenzo Giorio, Anna Bottin, Enrico Savio and Maurizio Galetto

### Feature session 9 (Dimensional /Machine tool metrology)

FS9-1 Feature Speaker: Dr. Ankit Kumar

Enhancing Wear Resistance of IN 625 Alloy Through Parameter Optimization in Wire Arc Additive Manufacturing (OS20-19)

Ankit Kumar, Mayank Arun Sontakke, Gurminder Singh and Rahul S. Mulik

FS9-2 Feature Speaker: Dr. Osamu Sato

Optimization of multiple-orientation dimensional measurement on X-ray CT (GS12-08)

Osamu Sato, Mari Watanabe, Kazuya Matsuzaki, Mariko Kajima, Souichi Telada, Tsukasa Watanabe, Youichi Bitou and Toshiyuki Takatsuji

FS9-3 Feature Speaker: Prof. Charyar Mehdi-Souzani

Aggregation-value-based active sampling method for multi-sensor freeform surfaces measurement and reconstruction (GS12-13)

Gengxiang Chen, Yingguang Li, Charyar Mehdi-Souzani and Xu Liu

FS9-4 Feature Speaker: Dr. Yindi Cai

Volumetric error modeling and compensation for nine-axis and five-linkage turn-milling compound machine tool (GS13-02)

Yindi Cai, Daoyuan Dai, Bo Wen, Zihui Zhu, Xianglong Zhu, Zhigang Dong and Renke Kang